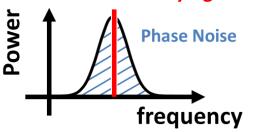
5<sup>th</sup> International Conference on Advanced Micro-Device Engineering (AMDE 2013)

## **Phase Noise Measurement with Delta-Sigma TDC**

Yusuke Osawa, D. Hirabayashi, N. Harigai, H. Kobayashi O. Kobayashi, K. Niitsu, T. Yamaguchi, N. Takai Electronic Engineering Department, Gunma University

## Oscillator Phase Noise

**Necessary signal** 



**Bad** influence in electronic system

- Interference in RF system
- ADC performance degradation

**Important** 

**Phase Noise Test** 

## **Conventional Method**



- Expensive spectrum analyzers
- Long measurement time (~10seconds)





Proposed Method

Using simple circuit



Delta-Sigma
Time-to-Digital Converter (TDC)

Low Cost , High Quality
Phase Noise Test

